IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Iori YOSHIKAWA

New U.S. National Phase of PCT/JP2005/000205

Filed: August 14, 2006 Docket No.: 127630

For: MEASUREMENT METHOD, TRANSFER CHARACTERISTIC MEASUREMENT

METHOD, ADJUSTMENT METHOD OF EXPOSURE APPARATUS, AND DEVICE

MANUFACTURING METHOD

PRELIMINARY AMENDMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Please consider the following:

Amendments to the Specification;

Remarks.